IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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In re Application of: Mak, et al.

§ Case: AMAT/8428/MASK/MASK-ETCH š

Serial No.: 10/754.321

Filed: January 9, 2004

Examiner: Deo, Duy Vu Nguyen

Group Art Unit: 1765

Confirmation No · 7484

Title: INTEGRATED PHASE ANGLE AND OPTICAL CRITICAL DIMENSION MEASUREMENT METROLOGY FOR **FFFD** FORWARD AND FEEDBACK

PROCESS CONTROL

MAIL STOP RCE Commissioner for Patents P.O. Box 1450

Alexandria, VA 22313-1450

Dear Sir:

RESPONSE TO FINAL OFFICE ACTION DATED JUNE 16, 2006

In response to the Final Office Action dated June 16, 2006, and Advisory Action dated August 17, 2006, having a shortened statutory period for response set to expire on September 16, 2006, please enter this response accompanying the Request for Continued Examination (RCE), and reconsider the claims pending in the application for the reasons discussed below. The Applicants believe that an RCE fee of \$790.00 is due in connection with this response and have been paid with the submission of this paper using the Patent Electronic Business Center. The Commissioner is hereby authorized to charge counsel's Deposit Account No. 20-0782 for any other fees. including additional extension of time fees or excess claim fees, required to make this response timely and acceptable to the Office.